

**Search Notes**

Application/Control No.

10/668,673

Examiner

Mark K. Han

Applicant(s)/Patent under  
Reexamination

TROCKI ET AL.

Art Unit

3767

**SEARCHED**

Class	Subclass	Date	Examiner
604	93.01	10/1/2006	mkh.
	118		
	131		
	152		
	154		
	181		
	187		
	533		
	534		
	535		
600	431		
	432		
128	dig. 1		
	dig. 12		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	3/20/2006	mkh.
EAST text search	10/1/2006	mkh.